

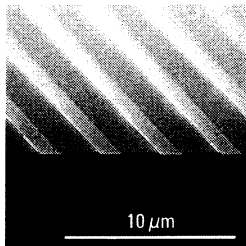
ULTRASHARP
CANTILEVERS & GRATINGS

TGZ01

[test structure]



TGZ01



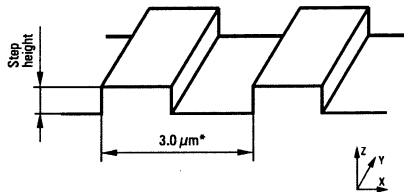
SEM image of the silicon grating TGZ01.

Grating Characteristics:

Active area: **3x3 mm**

Step height: **18 nm**

Accuracy: **1.0 nm**



* given for information only

Silicon calibration gratings of the TGZ series comprise a one-dimensional array of rectangular steps with a calibrated height value. The gratings are intended for Z-axis calibration of SPM scanners.